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Form PTO-1449 (Substitute)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Attorney Docket Number LAZE-01011US1	Serial/Patent Number 10/684,883
<i>Information Disclosure Statement BY APPLICANT (Use several sheets if necessary)</i>		Applicant/Patent Owner Thomas F. Rust			
		Filing/Issue Date 10/14/2003	Group Art Unit 2655		

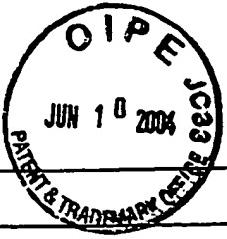
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Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
<i>Ap</i>	1	4,340,953	07/20/82	Iwamura et al.	369	126	05/07/80
	2	4,575,822	03/11/86	Quate	365	174	02/15/83
	3	4,829,507	05/09/89	Kazan et al.	369	126	08/15/88
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	5	4,916,688	04/10/90	Foster et al.	369	126	03/31/88
	6	4,945,515	07/31/90	Ooumi et al.	365	174	09/12/88
	7	4,962,480	10/09/90	Ooumi et al.	365	151	09/12/88
	8	4,987,312	01/22/91	Eigler	250	492.3	11/07/89
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	16	5,187,367	02/16/93	Miyazaki et al.	250	306	08/08/91
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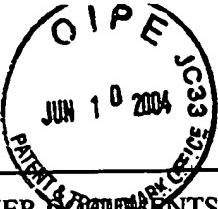
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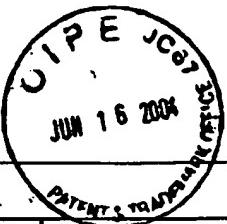
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